

# Detection of Light: Exercise 2

Set: Fri 13th Feb 2015,  
Due: Fri 20th Feb 2015

## 1 Carrier Mobility [3 marks]

- a The mobility of electrons in a Si photodetector at room temperature ( $T=300\text{K}$ ) is  $\mu = 1.35 \times 10^3 \text{ cm}^2 \text{ V}^{-1} \text{ s}^{-1}$ . What is its conductivity in  $\text{AV}^{-1} \text{ m}^{-1}$ , given that the intrinsic carrier concentration of electrons in Si at this temperature is  $n_0 = 1.5 \times 10^{10} \text{ cm}^{-3}$ .

[2 mark]

- b What is the electron mobility in the same photodetector  $T=250\text{K}$ ? State the physical reason behind this temperature dependence.

[2 marks]

## 2 Design of an intrinsic photoconductor [11 marks]

Consider an intrinsic silicon photoconductor operating at  $1 \mu\text{m}$  and constructed as shown in Fig. 1. Let its surface area,  $wl = 1 \text{ mm}^2$  in a square pixel configuration, operating at  $300 \text{ K}$ . Assume the detector breaks down when the bias voltage,  $V_b$ , exceeds  $60 \text{ mV}$ .

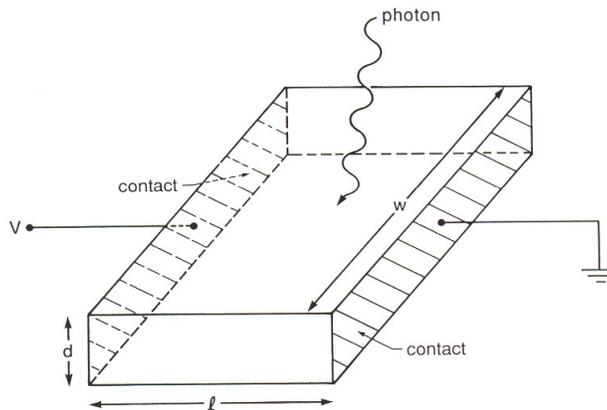


Figure 1: Photoconductor with transverse contacts.

- a The minimum detector thickness required for good quantum efficiency corresponds to one absorption length (photon mean free path length) in the material.

- i) Use the data in Fig. 2 to calculate the minimum detector thickness  $d$  for this detector. What is the corresponding quantum efficiency  $\eta$  of this detector, if reflection is neglected?

[3 marks]

- ii) What is a more realistic value of  $\eta$ , if reflection is now taken into account? Assume normal photon incidence on the detector surface and a refractive index for Si of  $n = 3.4$ .

[1 marks]

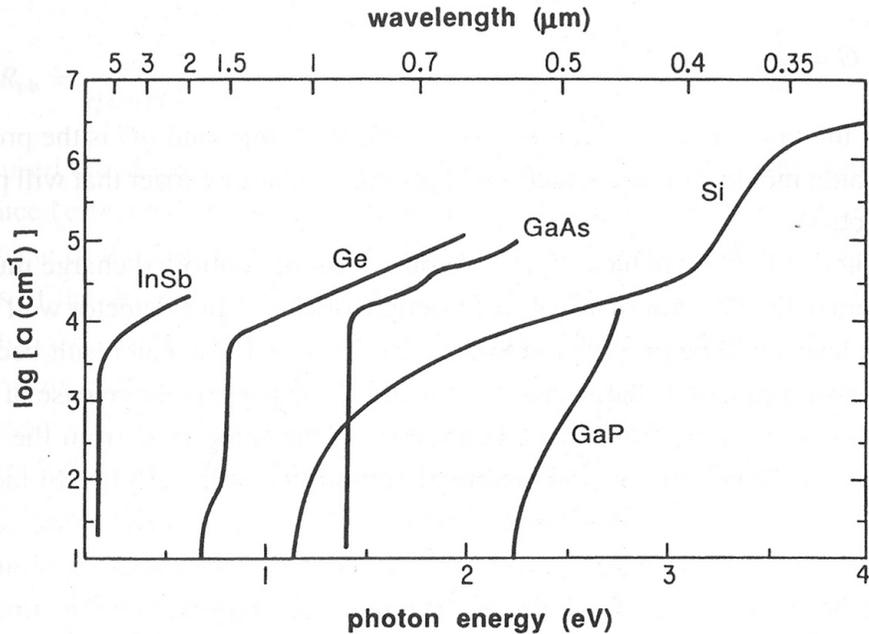


Figure 2: Linear absorption coefficients  $a$  for various semiconductors (on  $\log_{10}$  scale).

- b Calculate the responsivity  $S$  using your value of  $\eta$  in part a.ii, explicitly stating the units of your answer. The recombination time for Si under the given conditions is  $\tau = 1 \times 10^{-4}$  s. Assume the detector is operated at 10 mV below the breakdown voltage. What is the probability of any given photo-electron reaching the detector contact?

[3 marks]

- c i) Calculate the dark resistance and hence dark current of the detector. Again, take the electron concentration in Si to be  $n_0 = 1.5 \times 10^{10} \text{ cm}^{-3}$ .

- ii) Calculate the photo-current when the detector is illuminated by an astrophysical source with a photon flux of  $\phi = 10^5 \text{ } \gamma/\text{s}$ . What does this imply about the performance of a CCD made from these photoconductors, operating at room temperature?

[4 marks]

### 3 Detector Noise [6 marks]

For this question assume that the contribution of  $1/f$  noise is negligible in all cases.

- a Calculate the relative contributions of G-R and kTC noise for the detector in part 2, for an exposure time of 0.5s. In which noise regime is the detector operating?

[3 marks]

- b i) Derive an expression for the Noise-Equivalent Power (NEP) in the high-temperature regime, and calculate its value.

- ii) The detector is now cooled such that it operates in the the background-limited regime - calculate the new NEP value and contrast this with the answer to part i.

[3 marks]